

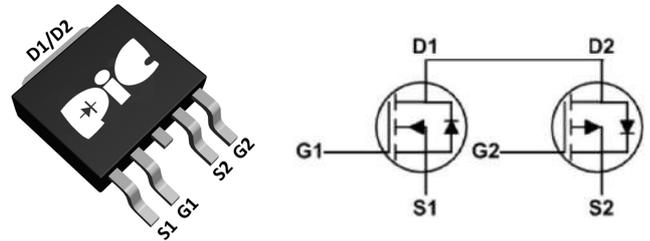
➤ General Description

This PAC69TX03X N&P Channel enhancement mode power field effect transistor is the high density trench technology and this advanced technology can provide excellent $R_{ds(On)}$ performance and efficiency for power switching and load switching application., this device also comply with the RoHS and Green Product requirement with full function reliability approved.

➤ Feature

- Super Low Gate Charge
- 100% EAS Guaranteed
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

➤ TO-252-4L



➤ Application

- Inverter
- H-Bridge

➤ Absolute Maximum Ratings

| Parameter | Symbol | Rating | | Units |
|--|-------------------------|------------|------------|--------------|
| | | N-Channel | P-Channel | |
| Drain-Source Voltage | V_{DS} | 60 | -60 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | ± 20 | V |
| Continuous Drain Current, $V_{GS} @ 10V^1$ | $I_D @ T_C=25^\circ C$ | 20 | -12 | A |
| Continuous Drain Current, $V_{GS} @ 10V^1$ | $I_D @ T_C=100^\circ C$ | 14 | -8.5 | A |
| Pulsed Drain Current ² | I_{DM} | 60 | -30 | A |
| Single Pulse Avalanche Energy ³ | EAS | 22 | 29.8 | mJ |
| Avalanche Current | I_{AS} | 21 | -24.4 | A |
| Total Power Dissipation ⁴ | $P_D @ T_C=25^\circ C$ | 50 | 50 | W |
| Storage Temperature Range | T_{STG} | -55 to 175 | -55 to 175 | $^\circ C$ |
| Operating Junction Temperature Range | T_J | -55 to 175 | -55 to 175 | $^\circ C$ |
| Thermal Resistance Junction-Ambient ¹ | $R_{\theta JA}$ | 62 | | $^\circ C/W$ |
| Thermal Resistance Junction-Case ¹ | $R_{\theta JC}$ | 3 | | $^\circ C/W$ |

➤ N-Channel Electrical Characteristics (T_J=25°C Unless otherwise noted)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|--|---------------------|---|------|------|------|------|
| Drain-Source Breakdown Voltage | BV _{DSS} | V _{GS} =0V, I _D =250uA | 60 | --- | --- | V |
| Static Drain-Source On-Resistance ² | R _{DS(ON)} | V _{GS} =10V, I _D =15A | --- | --- | 40 | mΩ |
| | | V _{GS} =4.5V, I _D =7A | --- | --- | 50 | |
| Gate Threshold Voltage | V _{GS(th)} | V _{GS} =V _{DS} , I _D =250uA | 1.0 | --- | 2.5 | V |
| Drain-Source Leakage Current | I _{DSS} | V _{DS} =48V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | uA |
| | | V _{DS} =48V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| Gate-Source Leakage Current | I _{GSS} | V _{GS} =±20V, V _{DS} =0V | --- | --- | ±100 | nA |
| Forward Transconductance | g _{fs} | V _{DS} =5V, I _D =15A | --- | 25.3 | --- | S |
| Total Gate Charge (10V) | Q _g | V _{DS} =48V, V _{GS} =10V, I _D =15A | --- | 19 | --- | nC |
| Gate-Source Charge | Q _{gs} | | --- | 2.5 | --- | |
| Gate-Drain Charge | Q _{gd} | | --- | 5 | --- | |
| Turn-On Delay Time | T _{d(on)} | V _{DD} =30V, V _{GS} =10V, R _G =3.3Ω I _D =15A | --- | 2.8 | --- | ns |
| Rise Time | T _r | | --- | 16.6 | --- | |
| Turn-Off Delay Time | T _{d(off)} | | --- | 21.2 | --- | |
| Fall Time | T _f | | --- | 5.6 | --- | |
| Input Capacitance | C _{iss} | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 1027 | --- | pF |
| Output Capacitance | C _{oss} | | --- | 65 | --- | |
| Reverse Transfer Capacitance | C _{rss} | | --- | 46 | --- | |

➤ Diode Characteristics

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|--|-----------------|---|------|------|------|------|
| Continuous Source Current ^{1,6} | I _S | V _G =V _D =0V, Force Current | --- | --- | 10 | A |
| Diode Forward Voltage ² | V _{SD} | V _{GS} =0V, I _S =1A, T _J =25°C | --- | --- | 1.2 | V |

Note :

1.Pulse width limited by maximum junction temperature.

2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%

3.The EAS data shows Max. rating . The test condition is V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=21A

4.Ensure that the channel temperature does not exceed 150°C.

5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

➤ P-Channel Electrical Characteristics (T_J=25° C Unless otherwise noted)

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|--|--------------|--|------|------|------|------|
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=-250\mu A$ | -60 | --- | --- | V |
| Static Drain-Source On-Resistance ² | $R_{DS(ON)}$ | $V_{GS}=-10V, I_D=-10A$ | --- | --- | 100 | mΩ |
| | | $V_{GS}=-4.5V, I_D=-5A$ | --- | --- | 125 | |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{GS}=V_{DS}, I_D=-250\mu A$ | -1.0 | --- | -2.5 | V |
| Drain-Source Leakage Current | I_{DSS} | $V_{DS}=-48V, V_{GS}=0V, T_J=25^\circ C$ | --- | --- | 1 | μA |
| | | $V_{DS}=-48V, V_{GS}=0V, T_J=55^\circ C$ | --- | --- | 5 | |
| Gate-Source Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | --- | --- | ±100 | nA |
| Forward Transconductance | g_{fs} | $V_{DS}=-5V, I_D=-4A$ | --- | 8.7 | --- | S |
| Total Gate Charge (-4.5V) | Q_g | $V_{DS}=-12V, V_{GS}=-4.5V, I_D=-6A$ | --- | 11.8 | --- | nC |
| Gate-Source Charge | Q_{gs} | | --- | 1.9 | --- | |
| Gate-Drain Charge | Q_{gd} | | --- | 6.5 | --- | |
| Turn-On Delay Time | $T_{d(on)}$ | $V_{DD}=-15V, V_{GS}=-10V, R_G=3.3\Omega, I_D=-1A$ | --- | 8.8 | --- | ns |
| Rise Time | T_r | | --- | 19.6 | --- | |
| Turn-Off Delay Time | $T_{d(off)}$ | | --- | 47.2 | --- | |
| Fall Time | T_f | | --- | 9.6 | --- | |
| Input Capacitance | C_{iss} | $V_{DS}=-15V, V_{GS}=0V, f=1MHz$ | --- | 1080 | --- | pF |
| Output Capacitance | C_{oss} | | --- | 73 | --- | |
| Reverse Transfer Capacitance | C_{rss} | | --- | 50 | --- | |

➤ Diode Characteristics

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|--|----------|--------------------------------------|------|------|------|------|
| Continuous Source Current ^{1,5} | I_S | $V_G=V_D=0V, \text{Force Current}$ | --- | --- | -10 | A |
| Diode Forward Voltage ² | V_{SD} | $V_{GS}=0V, I_S=-1A, T_J=25^\circ C$ | --- | --- | -1 | V |

Note :

1. Pulse width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
3. The EAS data shows Max. rating . The test condition is $V_{DD}=-25V, V_{GS}=-10V, L=0.1mH, I_{AS}=-24.4A$
4. Ensure that the channel temperature does not exceed 150°C.
5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

N-Ch and P-Ch Fast Switching MOSFET

$V_{DS}=60V, I_D=20A, R_{DS(ON)}=40m\Omega$

$V_{DS}=-60V, I_D=-12A, R_{DS(ON)}=100m\Omega$

N-Channel Typical Characteristics

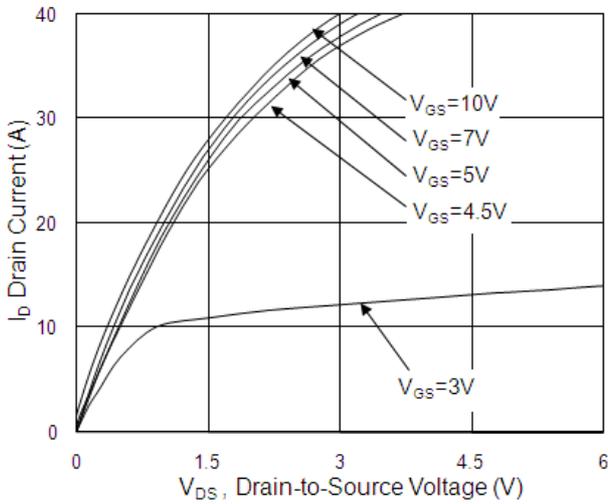


Fig.1 Typical Output Characteristics

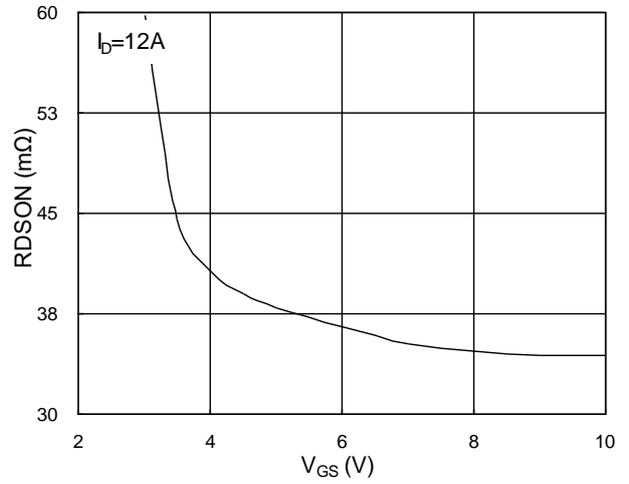


Fig.2 On-Resistance vs. G-S Voltage

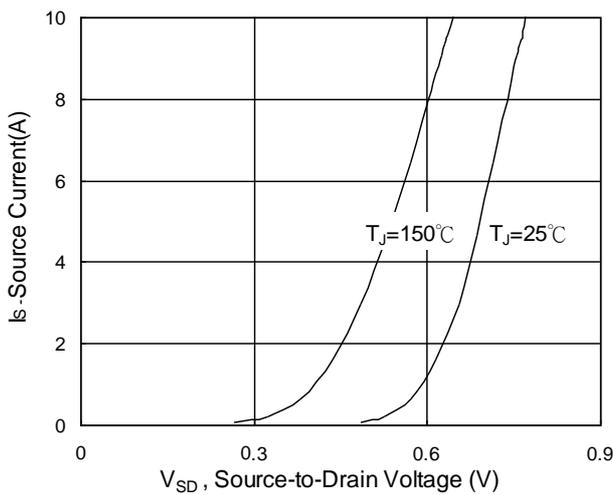


Fig.3 Source Drain Forward Characteristics

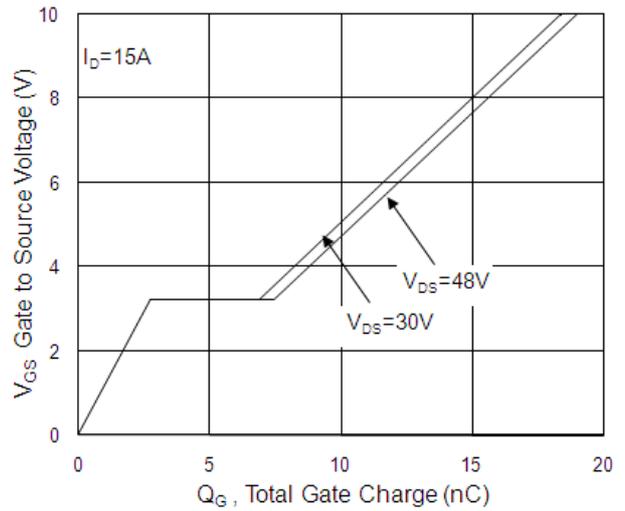


Fig.4 Gate-Charge Characteristics

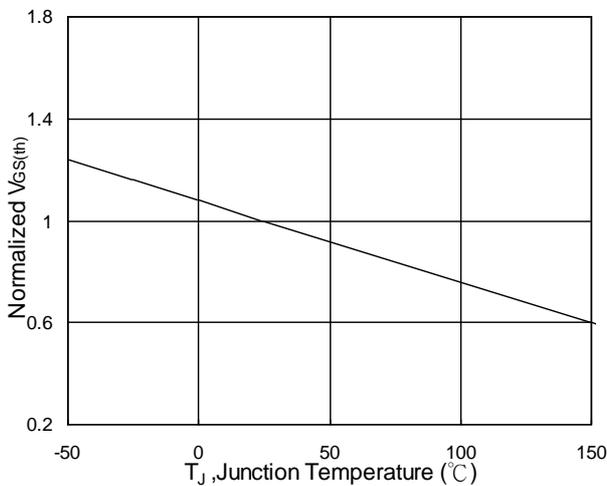


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

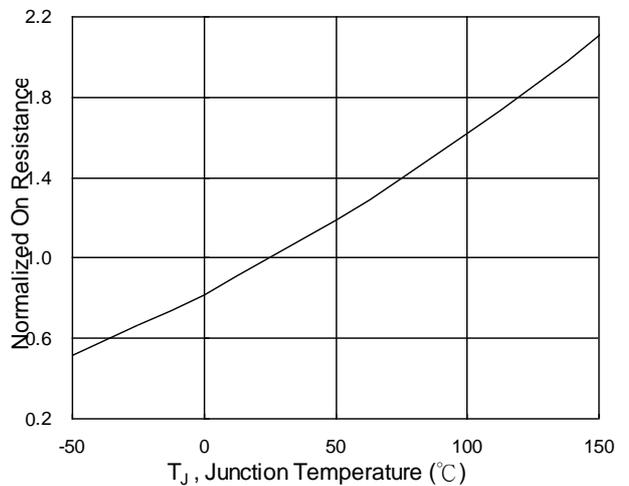


Fig.6 Normalized $R_{DS(ON)}$ vs. T_J

N-Ch and P-Ch Fast Switching MOSFET

$V_{DS}=60V, I_D=20A, R_{DS(ON)}=40m\Omega$

$V_{DS}=-60V, I_D=-12A, R_{DS(ON)}=100m\Omega$

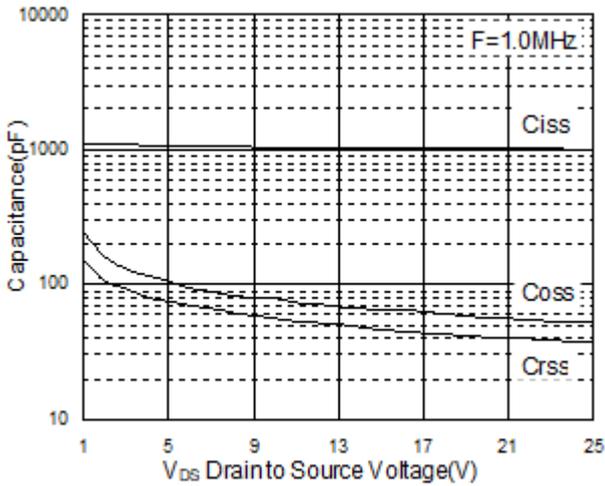


Fig.7 Capacitance

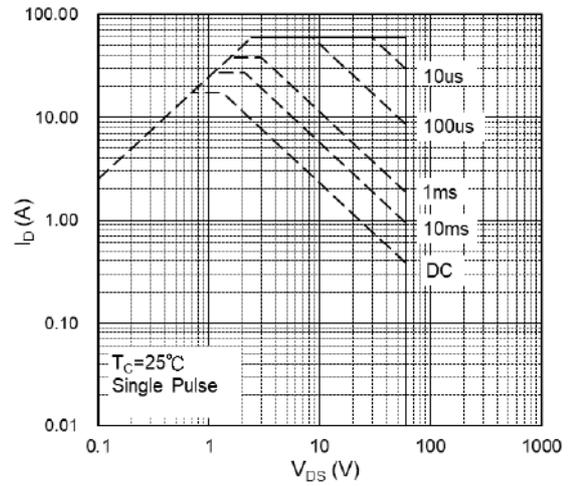


Fig.8 Safe Operating Area

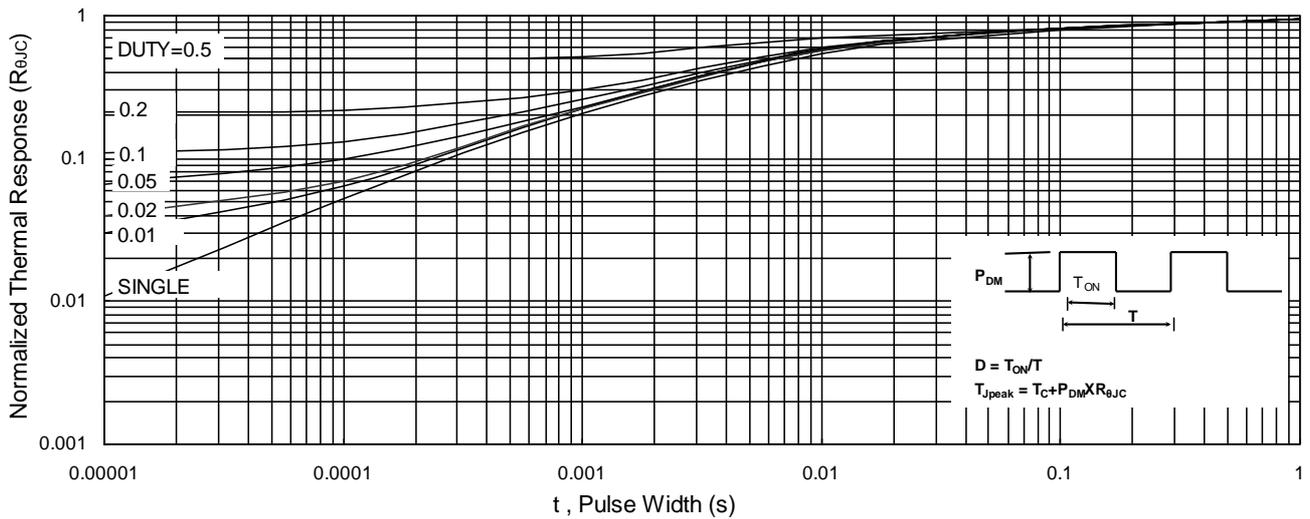


Fig.9 Normalized Maximum Transient Thermal Impedance

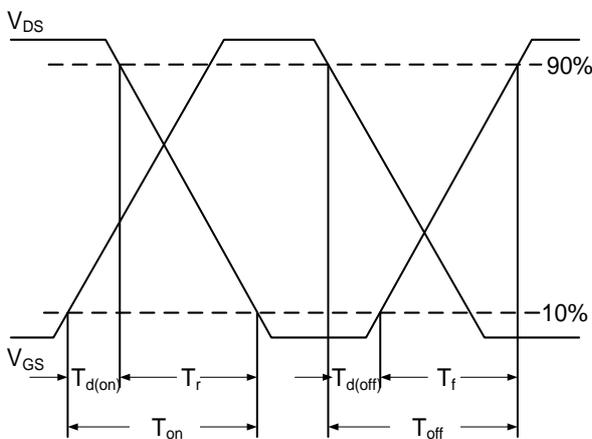


Fig.10 Switching Time Waveform

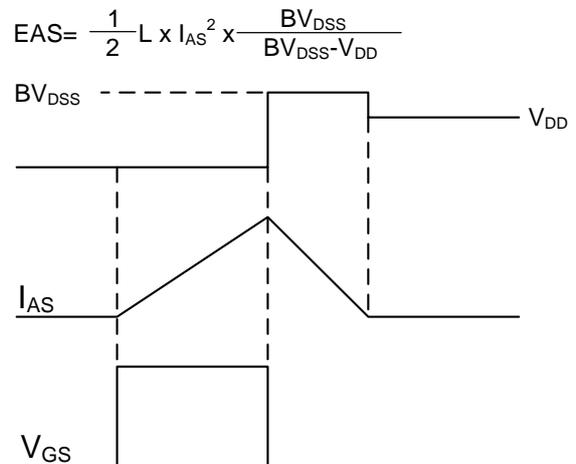


Fig.11 Unclamped Inductive Switching Waveform

N-Ch and P-Ch Fast Switching MOSFET

$V_{DS}=60V, I_D=20A, R_{DS(ON)}=40m\Omega$

$V_{DS}=-60V, I_D=-12A, R_{DS(ON)}=100m\Omega$

P-Channel Typical Characteristics

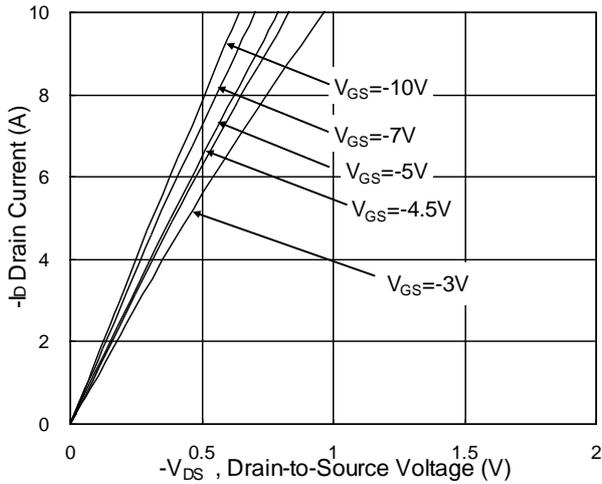


Fig.1 Typical Output Characteristics

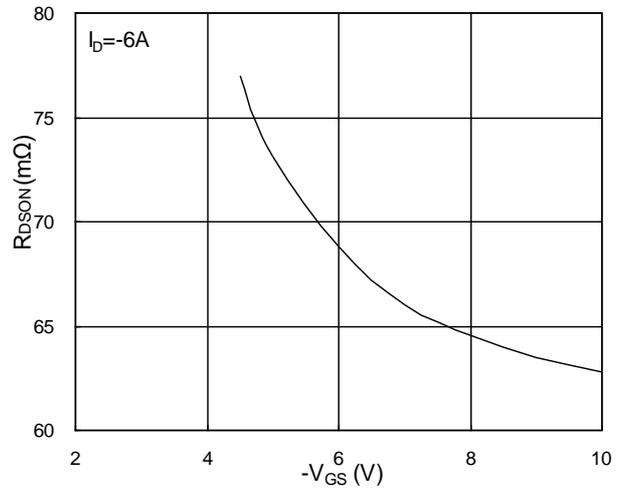


Fig.2 On-Resistance vs. G-S Voltage

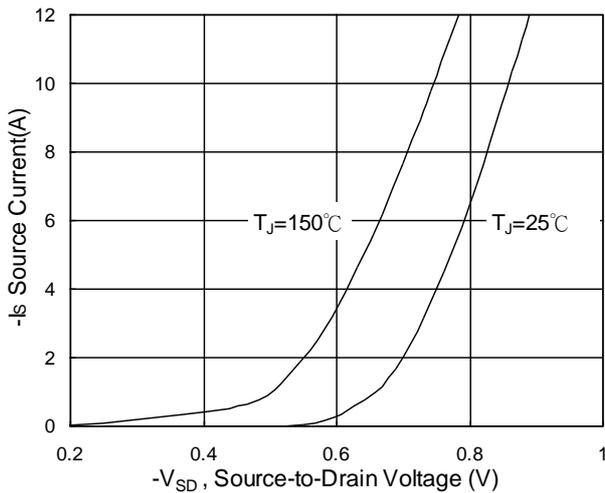


Fig.3 Source Drain Forward Characteristics

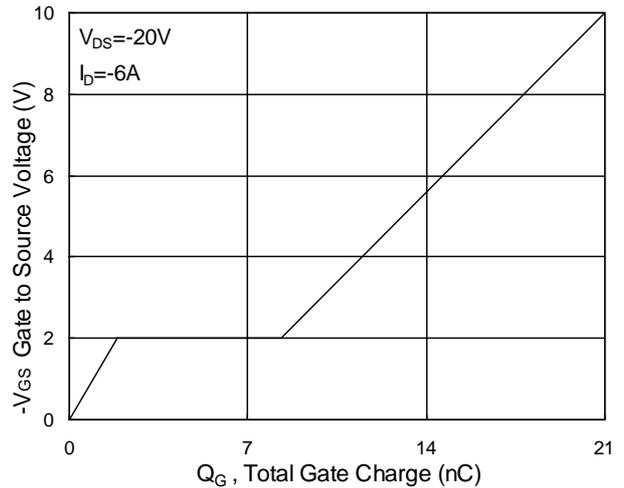


Fig.4 Gate-Charge Characteristics

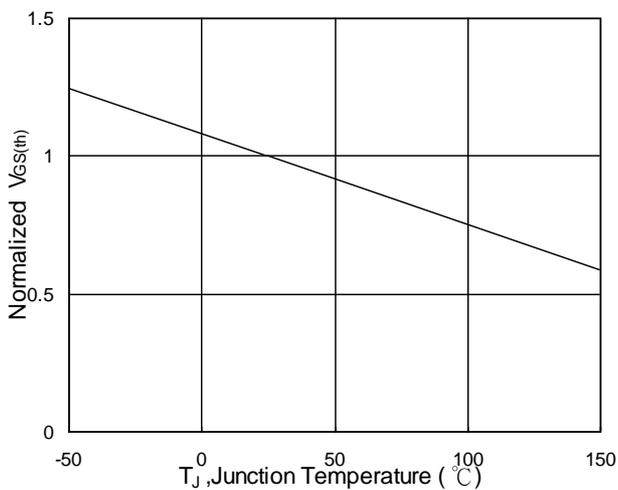


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

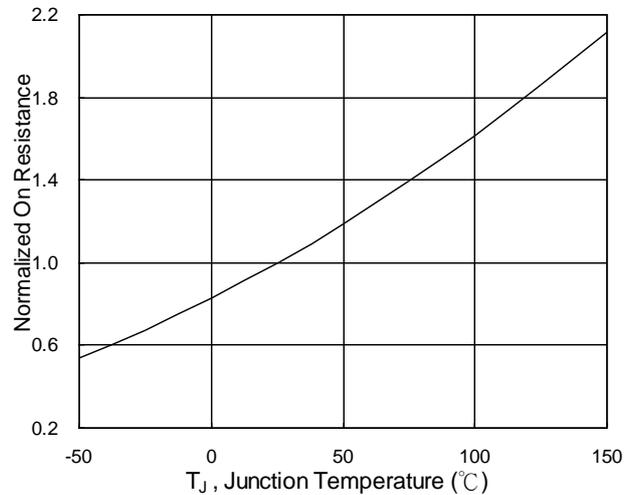


Fig.6 Normalized $R_{DS(ON)}$ vs. T_J

N-Ch and P-Ch Fast Switching MOSFET

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$V_{DS}=-60V, I_D=-12A, R_{DS(ON)}=100m\Omega$

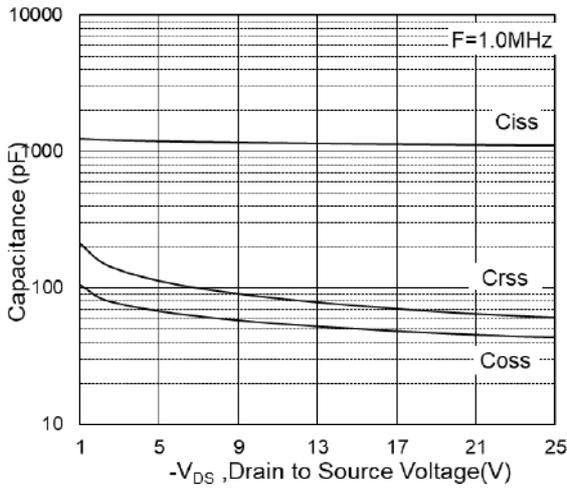


Fig.7 Capacitance

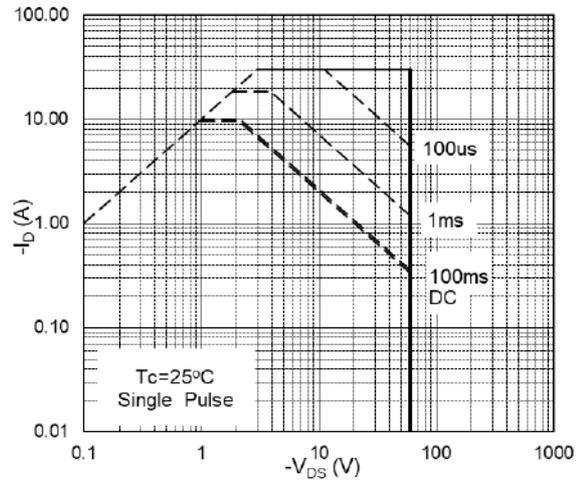


Fig.8 Safe Operating Area

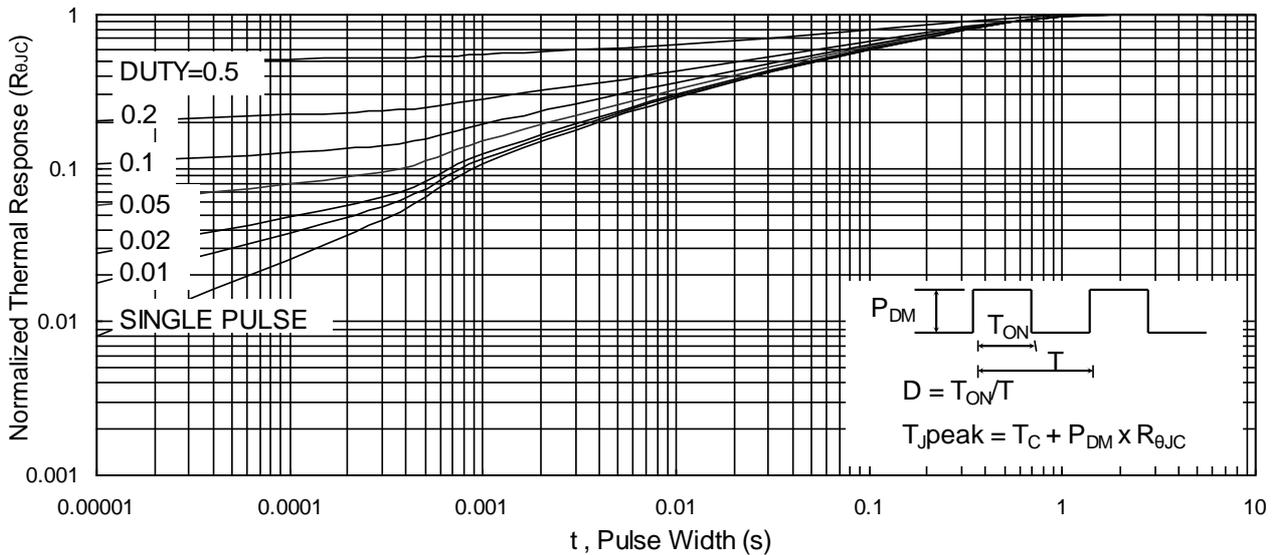


Fig.9 Normalized Maximum Transient Thermal Impedance

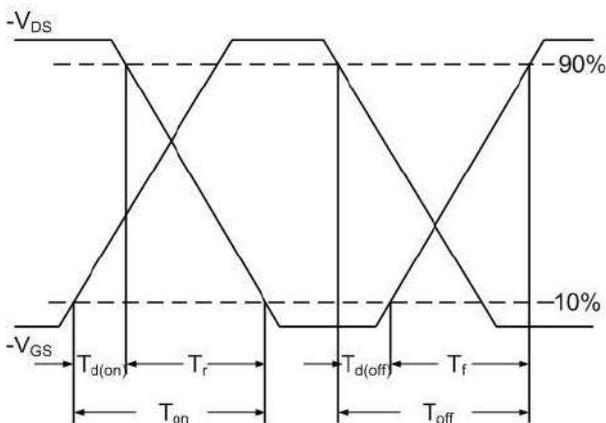


Fig.10 Switching Time Waveform

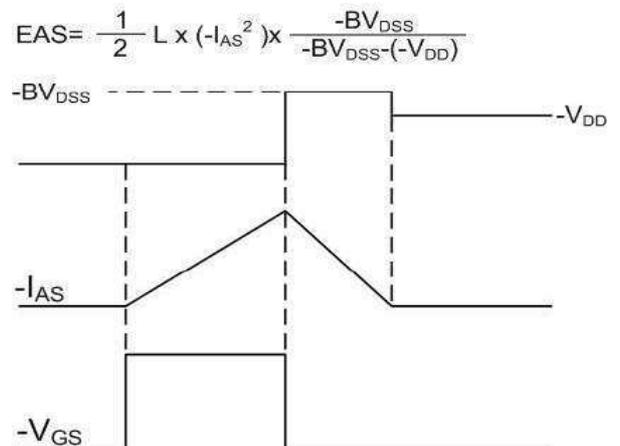


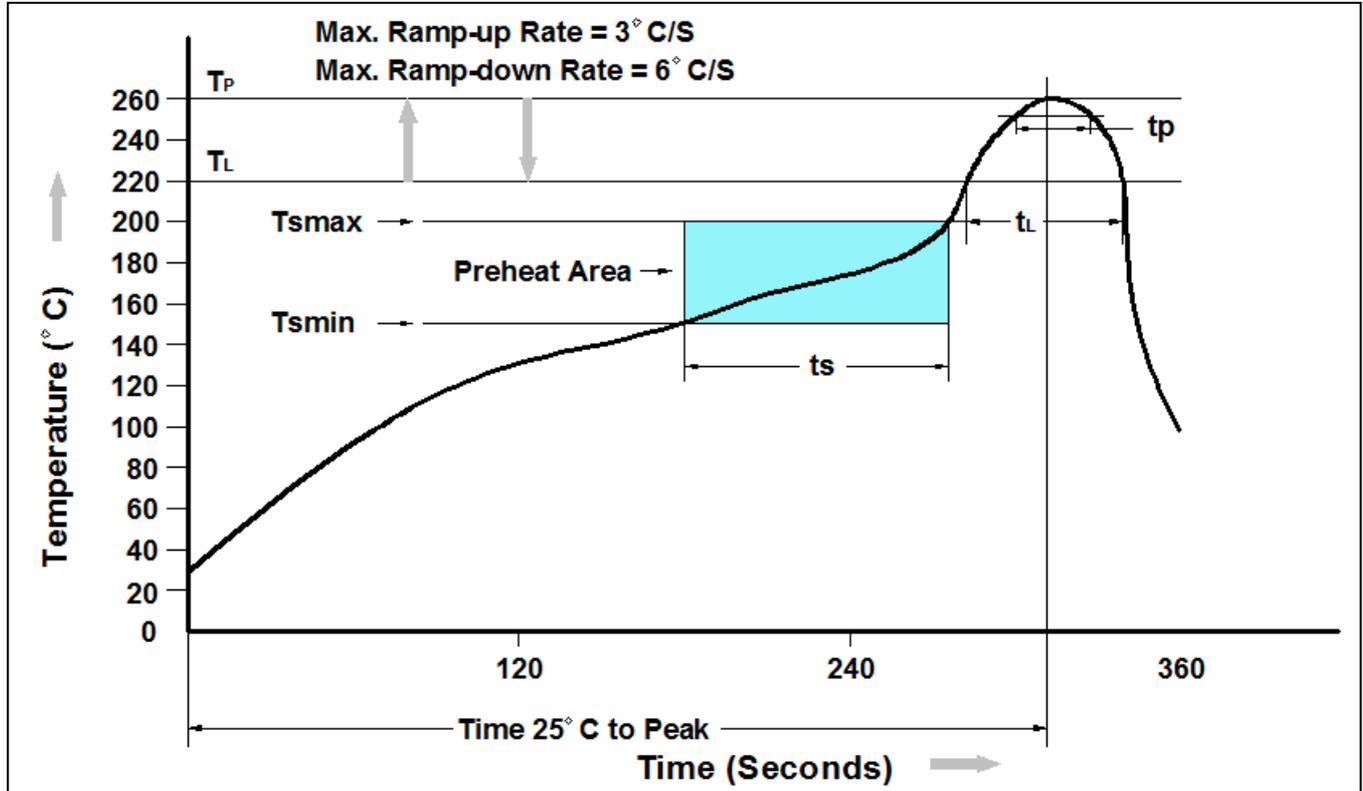
Fig.11 Unclamped Inductive Switching Waveform

N-Ch and P-Ch Fast Switching MOSFET

$V_{DS}=60V$, $I_D=20A$, $R_{DS(ON)}=40m\Omega$

$V_{DS}=-60V$, $I_D=-12A$, $R_{DS(ON)}=100m\Omega$

➤ Recommend IR Reflow Soldering Thermal Profile

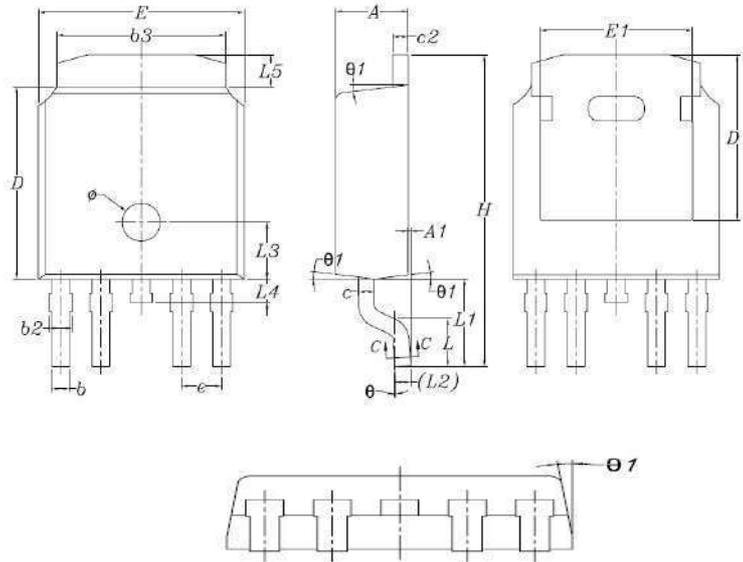


| Profile Feature | Pb-Free Assembly Profile |
|---|--------------------------|
| Temperature Min. (T _{smin}) | 150°C |
| Temperature Max. (T _{smax}) | 200°C |
| Time (t _s) from (T _{smin} to T _{smax}) | 60-120 seconds |
| Average Ramp-up Rate (t _L to t _P) | 3°C/second max. |
| Liquidous Temperature (T _L) | 217°C |
| Time (t _L) Maintained Above (T _L) | 60 – 150 seconds |
| Peak Temperature | 260°C +0°C / -5°C |
| Time (t _P) within 5°C of actual Peak Temperature | 30 seconds |
| Ramp-down Rate (T _P to T _L) | 6°C/second max |
| Time 25°C to Peak Temperature | 8 minutes max. |

➤ Ordering Information

| Part Number | Description | Quantity |
|-------------|----------------|----------|
| PAC69TX03X | TO-252-4L Reel | 2500 pcs |

➤ Package Information (TO-252-4L)



| SYMBOLS | MILLIMETERS | | INCHES | |
|---------|-------------|--------|----------|--------|
| | MIN | MAX | MIN | MAX |
| A | 2.180 | 2.400 | 0.0860 | 0.0950 |
| A1 | - | 0.127 | - | 0.0050 |
| b | 0.508 | 0.711 | 0.0200 | 0.0280 |
| b2 | 0.610 | 0.790 | 0.0240 | 0.0310 |
| b3 | 5.184 | 5.461 | 0.2041 | 0.2150 |
| c | 0.460 | 0.610 | 0.0181 | 0.024 |
| c2 | 0.460 | 0.610 | 0.0181 | 0.024 |
| D | 6.000 | 6.223 | 0.2362 | 0.2450 |
| D1 | 5.050 | -- | 0.1988 | -- |
| E | 6.350 | 6.731 | 0.2500 | 0.2650 |
| E1 | 4.320 | -- | 0.1700 | -- |
| e | 1.170 | 1.370 | 0.0461 | 0.0539 |
| H | 9.500 | 10.300 | 0.3740 | 0.4055 |
| L | 1.380 | 1.780 | 0.0540 | 0.0700 |
| L1 | 2.400 | 3.000 | 0.0945 | 0.1181 |
| L2 | 0.508BSC | | 0.020BSC | |
| L3 | 1.600 | 2.000 | 0.0630 | 0.0787 |
| L4 | -- | 1.016 | -- | 0.04 |
| L5 | 0.889 | 1.270 | 0.035 | 0.05 |
| θ | 0° | 10° | 0° | 10° |
| θ1 | 0° | 15° | 0° | 15° |
| ∅ | 1.050 | 1.350 | 0.0413 | 0.0531 |

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